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INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
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Sheet 1 of 1

Complete If Known	
Application Number	10/085,507
Filing Date	02/26/2002
First Named Inventor	John W. Orcutt
Group Art Unit	2872
Examiner Name	Shaffer, Ricky D. Pritchett
Attorney Docket No.	TI-32675

U.S. PATENT DOCUMENTS						
Exam. Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (If known)			
AA	6,094,293			Yokoyama, et al	07/25/2000	
AB						
AC						
AD						
AE						
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AH						

FOREIGN PATENT DOCUMENTS								
Exam. Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Office ³	Number ⁴	Kind Code ² (if known)				
BA	EP	0 962 796 A2			Congdon, et al	12/08/1999		
BB	DE	42 35 593 A1			Reicheneder	10/21/1993		
BC								
BD								
BE								
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS								
Exam. Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					T ²	
CA	KIM, "A laser-based 2-dimensional angular deflection measurement system for tilting microplates", Sensors Actuators, 86 (2000), pages 141-147, Elsevier, BNSDOCID: <XP 4224542A 1 >.							
CB	CHUNG, "Measurements of a fabricated micro mirror using a lateral-effect position-sensitive photodiode", Electronics, IEEE Inc. New York, U.S., vol. 45, no. 6, 1 December 1998 (1998-12-01), pages 861-865, XP000789096, ISSN: 0278-0046, abstract, pages 861-865.							
CC	TUANTRANONT, "Smart phase-only micromirror array fabricated by standard CMOS process", Proceedings IEEE Thirteenth Annual International Conference on Micro Electro Mechanical Systems, Miyazaki, Japan, 23-27 Jan. 2000, pages 455-460.							
CD								
CE								
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Examiner Signature	<i>plus 2 Pritchett</i>	Date Considered	5/24/04
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